Tessy V2.5 Features

Support for Tanto2 multiTEST

The new Tanto2 multiTEST hardware from Hitex allows stimulating and measuring the hardware input and output signals. The input values for those signals and the expected output may be specified as usual within the Test Data Editor TDE.

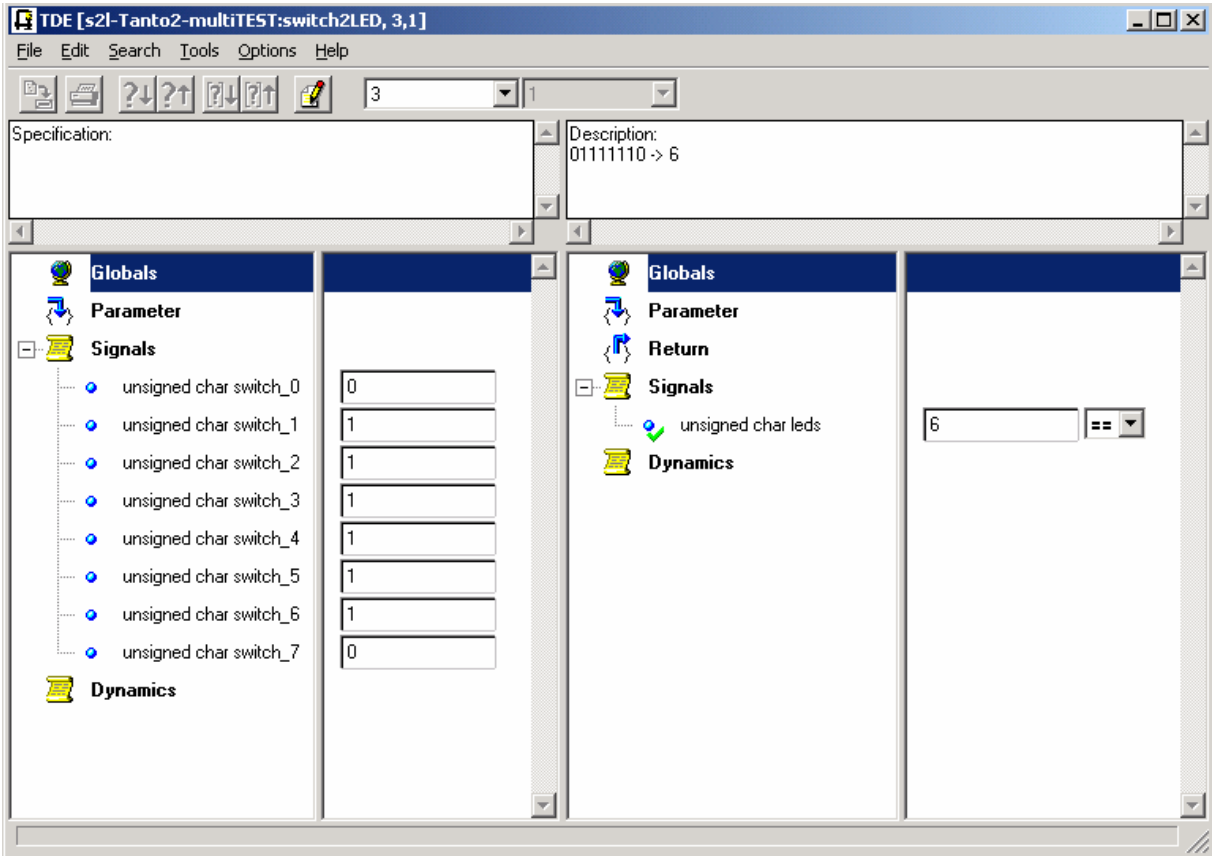

Fig.: Signals in the TDE

The input settings for the signals will be transmitted to Tanto2 multiTEST before execution of the respective test step. Then the test object will be executed and the measured signals will be acquired from Tanto2 multiTEST and stored into the test database of Tessy. This allows easy and reproducible hardware related testing on the unit test level.

Additional Microcontrollers Supported

Additional microcontrollers supported are from Freescale (DSP568E and PPC5xxx) and from Renesas (CCR32, NC30, and SH).

MC/DC and MCC Measurement

The coverage measurement has been enhanced to support Modified Condition / Decision Coverage (MC/DC) and Multiple Condition Coverage (MCC). Both measurements may be combined with the existing C1 (branch / decision) coverage measurement.

```
File      : C:\tessy\source\mcdc.c
Function  : mcdc_test
Line      : 6
Condition : ((A || B) && (C || D))
Coverage  :  80.00%

| A | B | C | D |
+---+---+---+---+---
| 0 | 0 | - | - | 1.1
| 0 | 1 | 0 | 1 | 2.1
| 1 | - | 0 | 0 | 3.1
| 1 | - | 0 | 1 | 4.1
| 1 | - | 1 | - |
```

Fig.: Four tests covered 4 of 5 atomic value combinations necessary for 100% MC/DC coverage

The MC/DC coverage includes the calculation of the required atomic value combinations for each condition within the test object. This helps developers in finding the required combinations for full MC/DC coverage.

Advanced Stubs for Local Functions

Tessy now allows specifying Advanced Stubs also for local functions within the current source file of the test object. This provides more flexibility when testing complex test objects which call many local functions. Up to now, only normal stub functions could be used.

Test Object Specific Stub Functions

It may now be specified individually for each test object, whether normal stubs or advanced stubs shall be used for different test objects, which call the same sub function.

Improved WORD Report Generation

The WORD report scripts have been changed to use RTF for the test data part of the document. This speeds up creation of the reports significantly.

Improved Configuration

The environment editor TEE allows to create individual configuration files that may be assigned to a project database (PDB).

